

Form 1449*	Atty. Docket No.: 303.382US2	Serial No. Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Applicant: Joseph E. Geusic et al.	
	Filing Date: Herewith	Group: Unknown

## U.S. PATENT DOCUMENTS

**Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WSL	3,968,564	07/13/1976	Springthorpe, A.J.	29	580	04/30/75
	4,920,070	04/24/1990	Mukai, R.	437	173	11/27/87
	4,970,578	11/13/1990	Tong, E.K., et al.	357	81	09/28/88
	5,128,831	07/07/1992	Fox, III, A.C., et al.	361	396	10/31/91
	5,221,633	06/22/1993	Holm, P.M., et al.	437	51	09/09/91
	5,352,998	10/04/1994	Tamino, N.	333	247	10/01/93
	5,362,976	11/08/1994	Suzuki, K.	257	81	10/26/92
	5,409,563	04/25/1995	Cathey	156	643	02/26/93
	5,489,554	02/06/1996	Gates, J.L.	437	208	02/04/94
	5,532,506	07/02/1996	Tserng, H.Q.	257	276	11/14/94
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	5,641,545	06/24/1997	Sandhu, G.S.	427	573	06/07/95
	5,656,548	08/12/1997	Zavracky, P.M., et al.	438	23	09/19/95
	5,682,062	10/28/1997	Gaul, S.J.	257	686	06/05/95
	5,729,038	03/17/1998	Young, W.R., et al.	257	460	12/15/95
	5,742,100	04/21/1998	Schroeder, J.A., et al.	257	778	03/27/95
	5,760,478	06/02/1998	Rozso, F.M., et al.	257	777	08/20/96
	5,767,001	06/16/1998	Bertagnolli, E., et al.	438	455	05/22/94
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	5,834,849	11/10/1998	Lane, C.F.	257	786	02/13/96
	5,844,289	12/01/1998	Teranishi, N., et al.	257	432	05/21/97
	5,858,814	01/12/1999	Goossen, K.W., et al.	438	107	12/12/96
	5,897,333	04/27/1999	Goossen, K.W., et al.	438	455	03/14/97
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	5,902,118	05/11/1999	Hubner, H.	438	106	07/03/95
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	5,952,665	09/14/1999	Bhargava, R.N.	250	483.1	11/28/97

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						Yes	No
WSL	03-013907	01/22/1991	Japan	G02B	6/12		
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	05-145060	06/11/1993	Japan	H01L	29/44		
	91/11833	08/08/1991	PCT	H01R	9/00		
	94/05039	03/03/1994	PCT	H01L	23/48		

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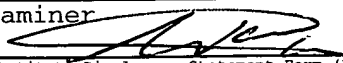
**Examiner						Translation
n	Indeument Number	Date	Country	Class	Subclass	Yes
No						

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WSL	Forbes, L., et al., "Resonant Forward-Biased Guard-Ring Diodes for Suppression of Substrate Noise in Mixed-Mode CMOS Circuits", <u>Electronics Letters</u> , 31, 720-721, (April 1995)
	Foster, R., et al., "High Rate Low-Temperature Selective Tungsten", In: <u>Tungsten and Other Refractory Metals for VLSI Applications III</u> , V.A. Wells, ed., Materials Res. Soc., Pittsburgh, PA, 69-72, (1988)
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	Heavens, O., <u>Optical Properties of Thin Solid Films</u> , Dover Pubs. Inc., New York, 155-206, (1965)
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V	Masu, K., et al., "Multilevel Metallization Based on Al CVD", <u>1996 IEEE Symposium on VLSI Technology, Digest of Technical Papers</u> , Honolulu, HI, 44-45, (June 11-13, 1996)

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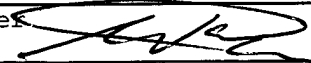
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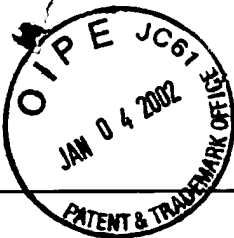
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WSE | Wooley, et al., "Experimental Results and Modeling Techniques for Substrate Noise in Mixed Signal Integrated Circuits", IEEE Journal of Solid State Circuits, Vol SC-28, 420-30, (1993)

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Sheet 1 of 1

Form 1449\*

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Serial No. 09/618,648

INFORMATION DISCLOSURE STATEMENT  
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(Use several sheets if necessary)

Applicant: Joseph E. Geusic et al.

Filing Date: July 18, 2000

Group: 2814

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						If Appropriate
WSL	5,416,872	05/16/1995	Sizer, II, T., et al.	385	92	07/06/93
↓	6,150,188	11/21/2000	Geusic, J.E., et al.	438	31	02/26/98
↓	6,181,864	01/30/2001	Jang, W., et al.	385	137	08/13/98
↓	6,198,168	03/06/2001	Geusic, J.E., et al.	257	774	01/20/98

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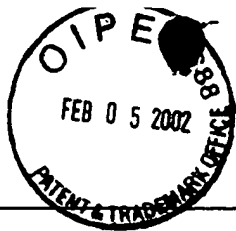
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**Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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	5,963,088	10/05/1999	Czarnul, Z., et al.	330	69	07/29/97
	6,122,187	09/19/2001	Ahn, K.Y., et al.	365	63	11/23/98
	6,143,616	11/07/2000	Geusic, J.E., et al.	438	389	08/22/97
	6,187,677	02/13/2001	Ahn, K.Y.	438	667	08/22/97
	6,281,042	08/28/2001	Ahn, K.Y., et al.	438	108	08/31/98

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**Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No
	56-055067	05/15/1981	Japan	H01L	23/52	

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